# International Rectifier

#### **Features**

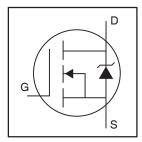
- Logic Level
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free

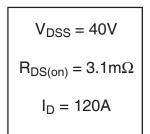
### **Description**

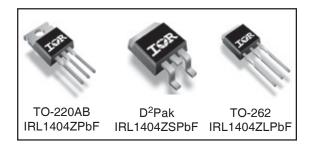
This HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

# IRL1404ZPbF IRL1404ZSPbF IRL1404ZLPbF

HEXFET® Power MOSFET







**Absolute Maximum Ratings** 

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	200 (9)	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	140⑨	А
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	120⑨	
I <sub>DM</sub>	Pulsed Drain Current ①	790	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	230	W
	Linear Derating Factor	1.5	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 16	V
E <sub>AS (Thermally limited)</sub>	Single Pulse Avalanche Energy ②	220	mJ
E <sub>AS</sub> (Tested )	Single Pulse Avalanche Energy Tested Value ®	490	
I <sub>AR</sub>	Avalanche Current ①	See Fig.12a, 12b, 15, 16	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ⑤		mJ
T <sub>J</sub>	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

#### Thermal Resistance

	Parameter	Тур.	Max.	Units
R <sub>eJC</sub>	Junction-to-Case		0.65	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface ⑦	0.50		
$R_{\theta JA}$	Junction-to-Ambient ⑦		62	
R <sub>eJA</sub>	Junction-to-Ambient (PCB Mount) ®		40	

#### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

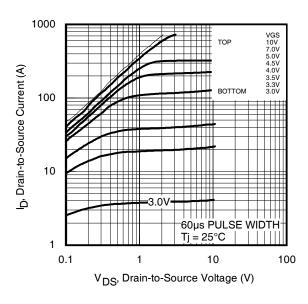
	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.034		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
			2.5	3.1		V <sub>GS</sub> = 10V, I <sub>D</sub> = 75A ③⑩
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			4.7	mΩ	V <sub>GS</sub> = 5.0V, I <sub>D</sub> = 40A ③
				5.9		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 40A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.4		2.7	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Transconductance	120			S	V <sub>DS</sub> = 10V, I <sub>D</sub> = 75A <sup>®</sup>
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 40V, V_{GS} = 0V$
				250		$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			200	nA	V <sub>GS</sub> = 16V
	Gate-to-Source Reverse Leakage			-200		V <sub>GS</sub> = -16V
Q <sub>q</sub>	Total Gate Charge		75	110		I <sub>D</sub> = 75A <sup>(1)</sup>
Q <sub>gs</sub>	Gate-to-Source Charge		28		nC	$V_{DS} = 32V$
$Q_{qd}$	Gate-to-Drain ("Miller") Charge		40			V <sub>GS</sub> = 5.0V ③
t <sub>d(on)</sub>	Turn-On Delay Time		19			V <sub>DD</sub> = 20V
t <sub>r</sub>	Rise Time		180			I <sub>D</sub> = 75A <sup>(1)</sup>
t <sub>d(off)</sub>	Turn-Off Delay Time		30		ns	$R_G = 4.0\Omega$
t <sub>f</sub>	Fall Time		49			V <sub>GS</sub> = 5.0V ③
L <sub>D</sub>	Internal Drain Inductance		4.5			Between lead,
					nH	6mm (0.25in.)
L <sub>s</sub>	Internal Source Inductance		7.5			from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		5080			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance		970			V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		570		pF	f = 1.0MHz
C <sub>oss</sub>	Output Capacitance		3310			$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
C <sub>oss</sub>	Output Capacitance		870			$V_{GS} = 0V, V_{DS} = 32V, f = 1.0MHz$
C <sub>oss</sub> eff.	Effective Output Capacitance		1280			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V  $

#### Source-Drain Ratings and Characteristics

	Parameter		Тур.	Max.	Units	Conditions
Is	Continuous Source Current		_	200 (9)		MOSFET symbol
	(Body Diode)				Α	showing the
I <sub>SM</sub>	Pulsed Source Current			790		integral reverse
	(Body Diode) ①					p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$ , $I_S = 75A$ (0), $V_{GS} = 0V$ (3)
t <sub>rr</sub>	Reverse Recovery Time		26	39	ns	$T_J = 25^{\circ}C$ , $I_F = 75A \oplus V_{DD} = 20V$
Q <sub>rr</sub>	Reverse Recovery Charge		18	27	nC	di/dt = 100A/µs ③
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			(turn-on is dominated by LS+LD)	

#### Notes:

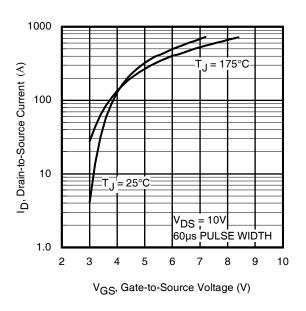
- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25^{\circ}C$ , L = 0.079mH,  $R_G = 25\Omega$ ,  $I_{AS} = 75A$ ,  $V_{GS} = 10V$ . Part not recommended for use above this value.
- $\P$  C<sub>oss</sub> eff. is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub> .
- S Limited by T<sub>Jmax</sub>, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑤ This value determined from sample failure population. 100% tested to this value in production.
- This is only applied to TO-220AB package.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 120A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.
- All AC and DC test condition based on former Package limited current of 75A.



 $(v) = \frac{1000}{(v)} = \frac{V_{GS}}{100} =$ 

Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics



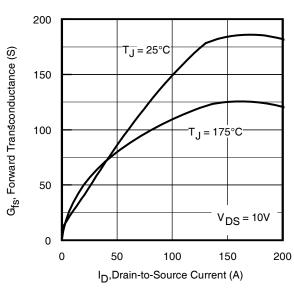
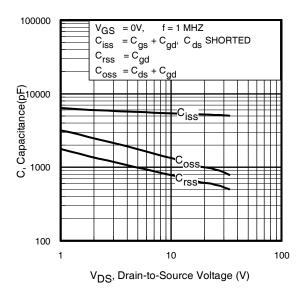


Fig 3. Typical Transfer Characteristics

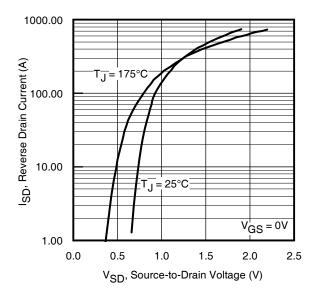
Fig 4. Typical Forward Transconductance vs. Drain Current



6.0 I<sub>D</sub>= 75A  $V_{DS} = 32V$ 5.0 V<sub>GS</sub>, Gate-to-Source Voltage (V) V<sub>DS</sub>= 20V 4.0 3.0 2.0 1.0 0.0 40 60 0 80 Q<sub>G</sub> Total Gate Charge (nC)

**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage

**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage



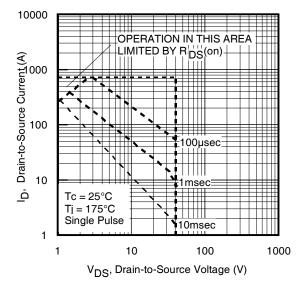
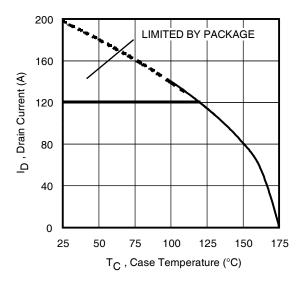
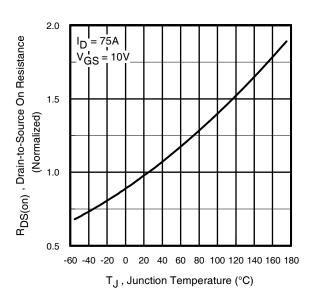


Fig 7. Typical Source-Drain Diode Forward Voltage

Fig 8. Maximum Safe Operating Area





**Fig 9.** Maximum Drain Current vs. Case Temperature

**Fig 10.** Normalized On-Resistance vs. Temperature

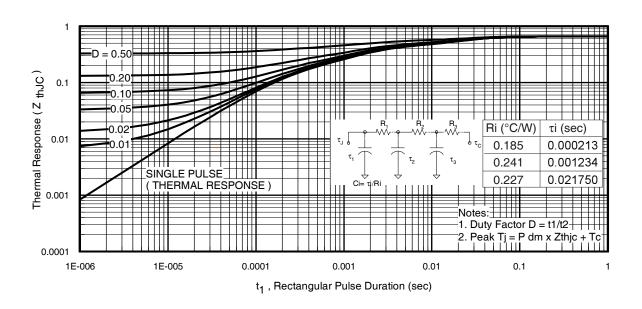


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

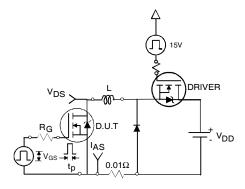


Fig 12a. Unclamped Inductive Test Circuit

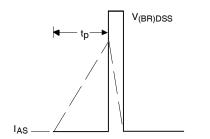


Fig 12b. Unclamped Inductive Waveforms

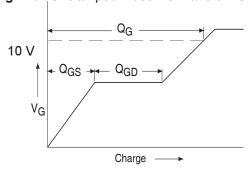
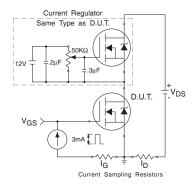
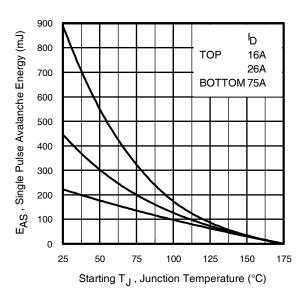


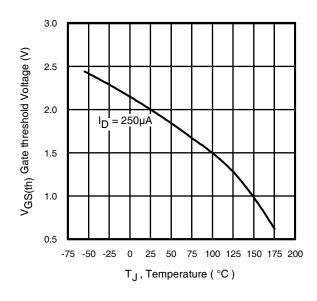
Fig 13a. Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit 6



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current



**Fig 14.** Threshold Voltage vs. Temperature www.irf.com

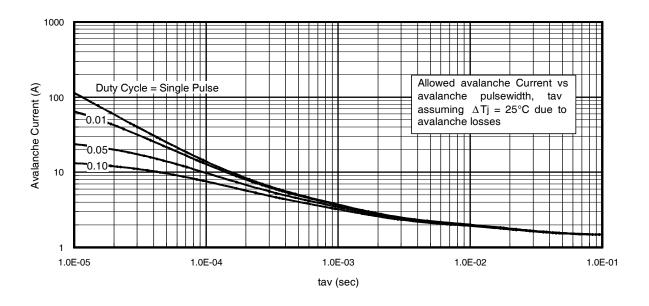


Fig 15. Typical Avalanche Current vs. Pulsewidth

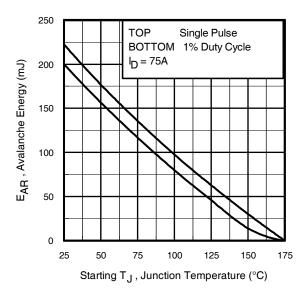


Fig 16. Maximum Avalanche Energy vs. Temperature

# Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long  $asT_{jmax}$  is not exceeded.
- Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 15, 16).  $t_{av}$  = Average time in avalanche.
  - $D = Duty cycle in avalanche = t_{av} \cdot f$

 $Z_{th,JC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D\;(ave)} &= 1/2\;(\;1.3\text{-BV-I}_{av}) = \triangle T/\;Z_{thJC}\\ I_{av} &= 2\triangle T/\;[1.3\text{-BV-Z}_{th}]\\ E_{AS\;(AR)} &= P_{D\;(ave)} \cdot t_{av} \end{split}$$

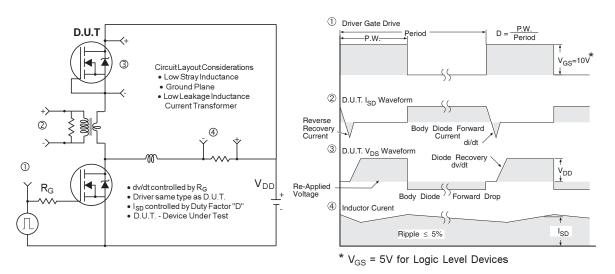


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

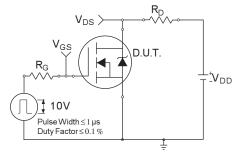


Fig 18a. Switching Time Test Circuit

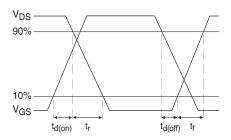
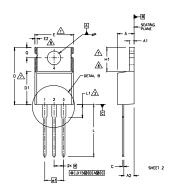
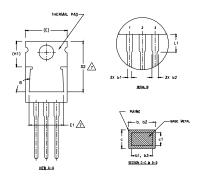


Fig 18b. Switching Time Waveforms

### TO-220AB Package Outline

Dimensions are shown in millimeters (inches)





- MINENSONING AND TOLERANCING PER ASME Y14.5 M- 1994.
  DIMENSONIS ARE SHOWN IN NOTES [MILLIMETERS].
  LEAD DIMENSON AND FINSH UNCONTROLLED IN L.1.
  DIMENSON D. & E DO NOT INCLUDE WICE THE MOLD FLASH
  SHALL NOT EXCELD .005 (0.127) PER SIDE. THESE DIMENSONIS ARE
  MEASURED AT THE OUTERMOSE STRUKTINGS OF THE PLASTIC BODY.
  DIMENSON 15 & c.1 APPLY TO BISE METAL ONLY.
  CONTROLLING DIMENSON: INCORT.
  THERMIAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E.H.1,02 & E1
  DIMENSON EX. AT ID GET ME. A ZONE WHERE STAMPING
  AND SINGULATION IRREGULARTIES ARE ALLOWED.

	DIMENSIONS							
SYMBOL	MILLIM	ETERS	INC	HES				
	MIN.	MAX.	MIN.	MAX,	NOTES			
Α	3,56	4,82	,140	,190				
A1	0.51	1.40	.020	.055				
A2	2,04	2,92	.080	,115				
ь	0.38	1.01	.015	.040				
ь1	0,38	0,96	,015	,038	5			
b2	1,15	1,77	.045	.070				
b3	1,15	1,73	.045	.068				
_ c	0.36	0.61	.014	.024				
c1	0.36	0.56	.014	.022	5			
D	14,22	16,51	,560	,650	4			
D1	8.38	9.02	.330	.355				
D2	12,19	12.88	.480	.507	7			
E	9.66	10.66	.380	.420	4,7			
E1	8,38	8,89	.330	,350	7			
e	2.54	BSC	.100 BSC					
e1	5.	08	,200 BSC					
H1	5.85	6.55	.230	.270	7,8			
L	12,70	14,73	.500	.580				
Lf	-	6.35	-	.250	3			
ø₽.	3.54	4.08	130	161				

.100

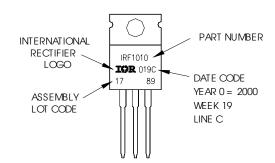
# TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF 1010

LOT CODE 1789

ASSEMBLED ON WW 19, 2000 IN THE ASSEMBLY LINE "C"

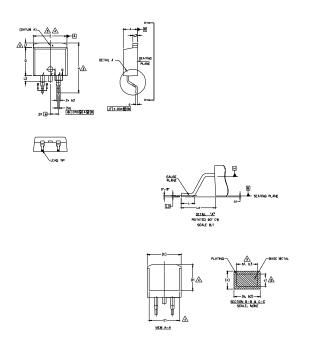
Note: "P" in assembly line position indicates "Lead-Free"



- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

# D<sup>2</sup>Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)



NOTES; 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994

2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED 0.127 [.006] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- B. OUTLINE CONFORMS TO JEDEC DUTLINE TO-263AB.

S Y		Ŋ				
BO	MILLIMETERS		INC	HES	NOT.	
L	MIN.	MAX.	MIN.	MAX.	Ė	
Α	4.06	4.83	.160	.190		
A1	0,00	0,254	,000	.010		
ь	0,51	0.99	.020	.039		
ь1	0,51	0.89	.020	.035	5	
b2	1,14	1,78	.045	,070		
b3	1,14	1,73	.045	,068	5	
С	0.38	0.74	.015	.029	5	
c1	0.38	0.58	.015	.023		
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	-	.270		4	
Ε	9.65	10.67	.380	.420	3,4	
E1	6.22	-	.245		4	
e	2.54	BSC	.100	BSC	1	
н	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	-	1.65	-	.066	4	
L2	1.27	1,78	-	.070		
L3	0,25	BSC	.010 BSC		1	
L4	4.78	5.28	.188	.208		

# LEAD ASSIGNMENTS HEXFET

1.- GATE 2, 4.- DRAIN 3.- SOURCE

IGBTs, CoPACK

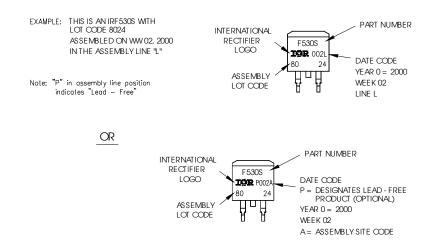
1.- GATE
2, 4.- COLLECTOR
3.- EMITTER

DIODES

2. 4.- CATHODE 3.- ANODE

\* PART DEPENDENT

# D<sup>2</sup>Pak (TO-263AB) Part Marking Information

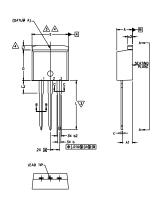


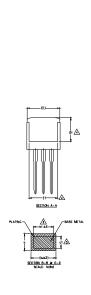
#### Notes:

- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

## TO-262 Package Outline

Dimensions are shown in millimeters (inches)





#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
  - 6. CONTROLLING DIMENSION: INCH.
  - 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S						
Ň			Ņ			
S Y M B O L	MILLIM	ETERS	INC	INCHES		
L	MIN.	MAX.	MIN.	MAX.	NOLES	
Α	4.06	4.83	.160	.190		
Α1	2.03	3.02	.080	.119		
b	0.51	0.99	.020	.039		
ь1	0.51	0.89	.020	.035	5	
b2	1,14	1.78	.045	.070		
b3	1,14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	-	.270	-	4	
Ε	9.65	10.67	.380	.420	3,4	
Εſ	6.22	-	.245		4	
е	2.54 BSC		.100			
L	13,46	14,10	.530	.555		
L1	-	1,65	-	.065	4	
L2	3,56	3,71	.140	.146		

#### LEAD ASSIGNMENTS

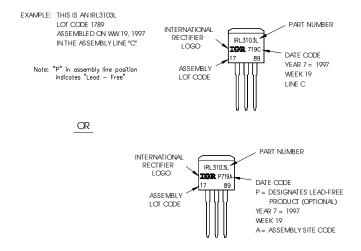
### <u>HEXFET</u>

- 1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

#### IGBTs. CoPACK

- 1,- GATE 2,- COLLECTOR 3.- EMITTER 4,- COLLECTOR

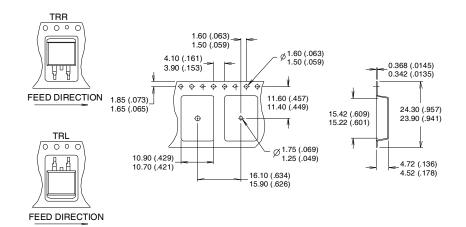
# TO-262 Part Marking Information

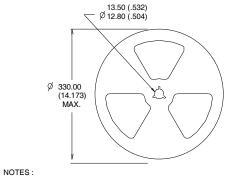


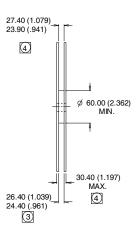
- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

### D<sup>2</sup>Pak Tape & Reel Infomation

Dimensions are shown in millimeters (inches)







- COMFORMS TO EIA-418.
  CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION MEASURED @ HUB.
  INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.

> International IOR Rectifier

IR WORLD HEADQUARTERS: 101N. Sepulveda blvd, El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information. 06/2012

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